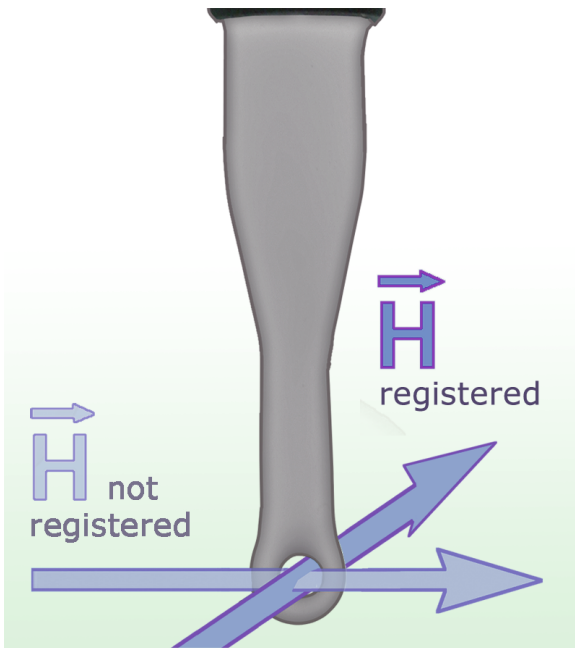


# XFS-R 3-1

Scanner Probe 30 MHz up to 6 GHz



## Short description

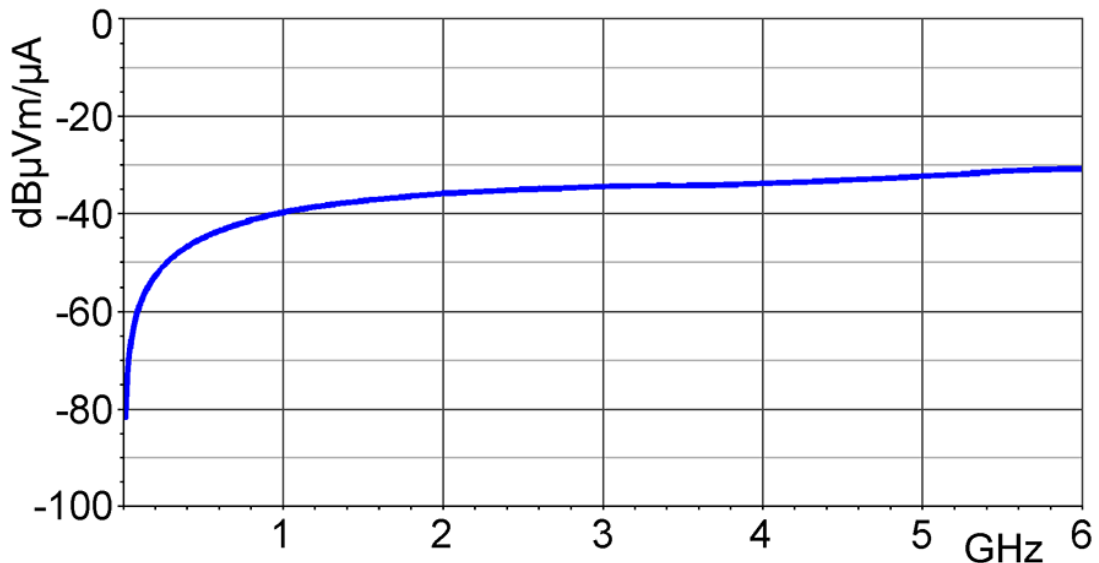
The XFS-R 3-1 scanner probe is designed for direct high-resolution measurements of RF magnetic fields on an assembly, e.g. around the pins and IC cases, conducting paths, decoupling capacitor, and EMC components.

The XFS-R 3-1 H-field scanner probe is suitable for measurements close to the components with high magnetic field strength. It has a current attenuating sheath and, therefore, is electrically shielded. It can be connected to a spectrum analyzer or an oscilloscope with a  $50 \Omega$  input. The H-field probe has an internal terminating resistance.

## Technical parameters

Frequency range	30 MHz ... 6 GHz
Resolution	$\approx 1$ mm
Probe head dimensions	$\varnothing \approx 3$ mm
Connector - output	SMA, male, jack

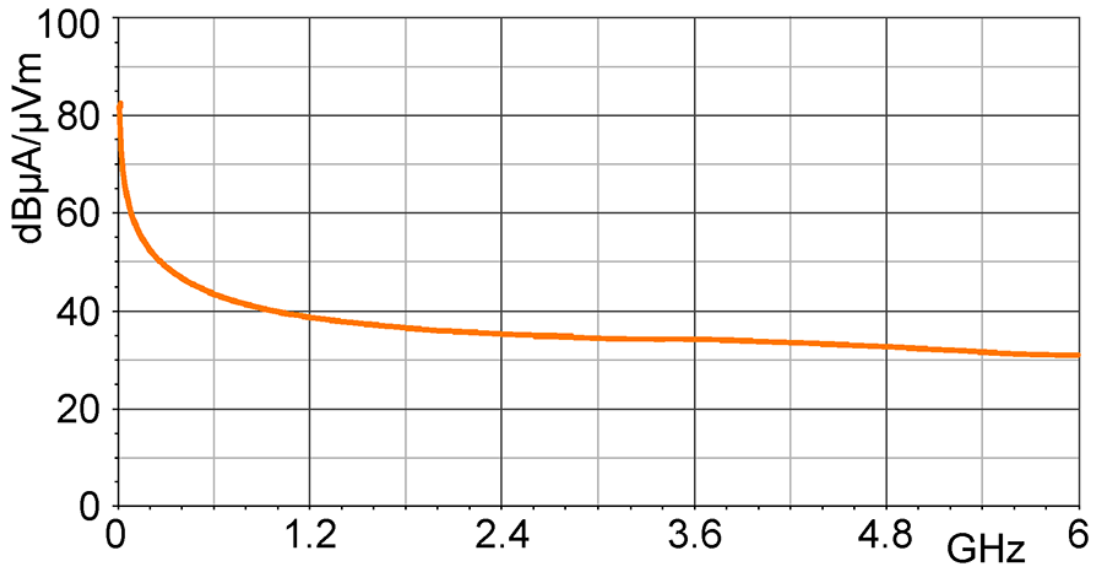
Frequency response [dB $\mu$ V] / [dB $\mu$ A/m]



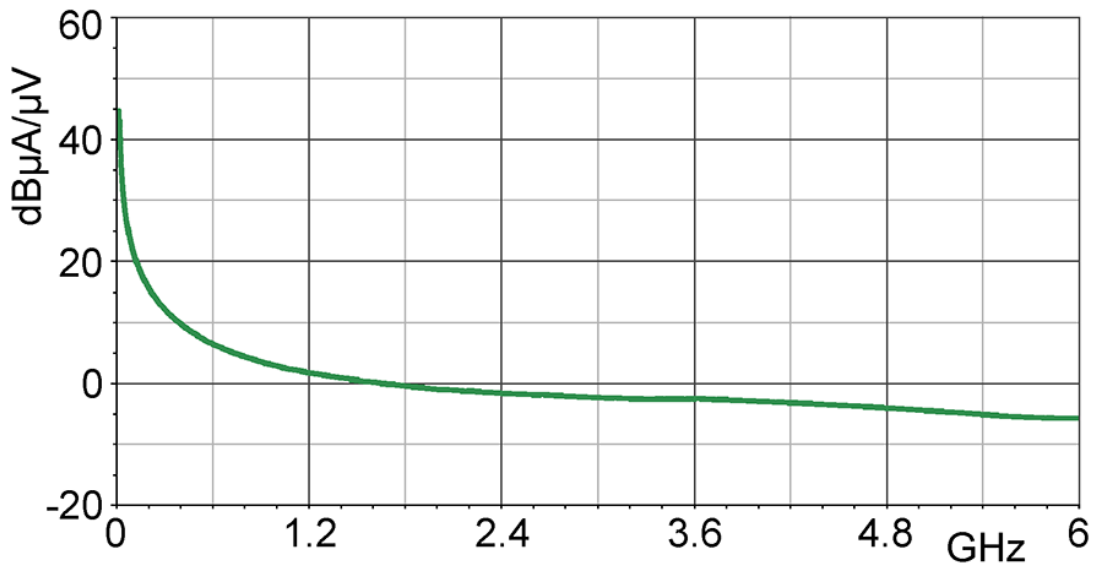
# XFS-R 3-1

Scanner Probe 30 MHz up to 6 GHz

H-field correction curve [dB $\mu$ A/m] / [dB $\mu$ V]



Current correction curve [dB $\mu$ A] / [dB $\mu$ V]



# XFS-R 3-1

Scanner Probe 30 MHz up to 6 GHz

## Measuring principles

